

Search Notes

Application N .

10/087,229

Examiner

Young J. Kim

Applicant(s)

CHOU ET AL.

Art Unit

1637

SEARCHED

Class	Subclass	Date	Examiner
435	6		
	91.1		
	91.2		
536	23.1		
	24.3		
	24.33	2/6/2004	YJK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Patent Database (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)		
STN Commercial Database: see enclosed search strategy for the list of databases		
See enclosed search strategies	2/6/2004	YJK